Single-Pulse RF Damage of GaAs FET Amplifiers

J.H. McAdoo, W.M. Bollen and R.V. Garver. "Single-Pulse RF Damage of GaAs FET Amplifiers." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 289-292.

Several GaAs MMIC (microwave monolithic integrated circuits) amplifiers have been tested for damage from single pulses of microwave power applied to the circuit input terminals. Damage characteristics are described and modeled.

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